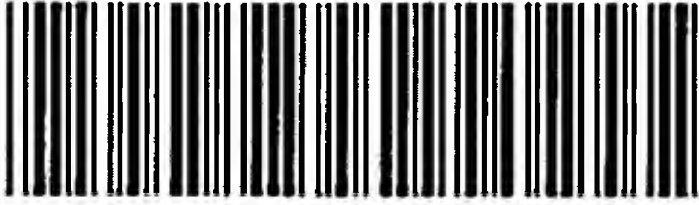


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/710,828	EDELSTEIN ET AL.	
	Examiner	Art Unit	
	Marcos D. Pizarro-Crespo	2814	

SEARCHED			
Class	Subclass	Date	Examiner
257	750-766	6/12/2006	MDP

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR